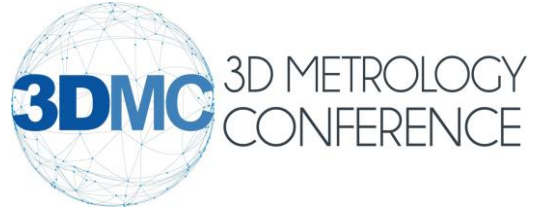




metrology



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Sponsors of the Poster Session — The 3D Metrology Conference 2024

Editor-in-Chief

Prof. Dr. Han Haitjema



MDPI

Aim and Scope

Metrology covers a broad range of areas, such as studies related to the following topics:

Website:

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- Traceability to SI units of complex measurement systems;
- Measurement theory in a broad context;
- Measurement uncertainty and uncertainty evaluation;
- Considerations on the fundamentals of measurement;
- Error separation methods;
- Novel methods inspired by the redefinition of the SI;
- Cyberphysical systems;
- Artificial intelligence, especially its effect on traceability;
- Machine learning for metrology;
- Precision measurement;
- Digital twins;
- Metrology for sustainable manufacturing;
- Precision manufacturing;
- Measurement techniques and devices;
- Interferometry;
- XCT measurements;
- Three-dimensional (3D) metrology;
- Frequency metrology;
- Surface metrology;
- Biomedical measurement;
- Virtual measurement;
- Power measurement.

Metrology (ISSN: 2673-8244) was selected for coverage in the **Scopus** indexing database on **15 July 2024**.



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Recently
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Keywords

- Portable coordinate metrology (PCM);
- Large-volume metrology (LVM);
- Close-range photogrammetry;
- Laser tracking;
- Three-dimensional (3D) surface inspection (from area scanning to detailed roughness);
- CMM technology advances;
- Computed tomography (CT) for metrology applications;
- Metrology-assisted manufacturing (e.g., machining and assembly);
- Robotic and automated PCM;
- Point-cloud analysis;
- Virtual metrology systems;
- Metrology integration with digital twins;
- Mixed robotic and human workspaces;
- Multiple object tracking;
- Three-dimensional (3D) data analysis for quality maintenance.

Special Issue

Developments in 3D Metrology Selected from the 3D Metrology Conference



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Guest Editors

Dr. Stephen Kyle,
Prof. Ben Hughes,
Prof. Dr. Stuart Robson and
Prof. Dr. Robert Schmitt

Deadline

30 November 2024

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Submission Link:

https://www.mdpi.com/journal/metrology/special_issues/MB7O54K700

Conference offer: no fees for first 5 accepted articles, 20% discount for others



Related publications within the scope of the conference 3DMC, which you are welcome to read.

[Outlier Elimination in Rough Surface Profilometry with Focus Variation Microscopy](#)

Four citations

[Development of a Toolchain for Automated Optical 3D Metrology Tasks](#)

Two citations

[3D Model-Based Large-Volume Metrology Supporting Smart Manufacturing and Digital Twin Concepts](#)

Five citations

[Spectroscopic Reflectometry for Optimizing 3D Through-Silicon-Vias Process](#)



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Thanks

Q&A

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